

The QCAD Framework for Quantum Device Modeling

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Modeling Quantum Dots

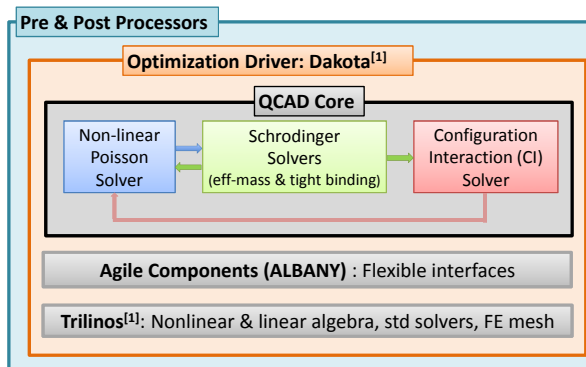
Goals

- Design guidance:** which double quantum dot layouts perform best?
- Device calibration:** given a specific dot device, what gate voltages lead to few-electron behavior (threshold voltage, dot-to-gate capacitances, etc.)?

Challenges

- many device layouts & material stacks
- large parameter space (many gates)
- defects / disorder
- complex geometries
- low temperature

Quantum Computer Aided Design (QCAD) Device Simulator



Development Goals

- Integration
- Flexibility
- High Throughput

Features

- Automatic differentiation
- Evaluation order determined by graphs
- Distributed parallel computing
- All Sandia-developed!

Self-Consistent Poisson-Schrodinger (P-S)

Coupled Poisson equation:

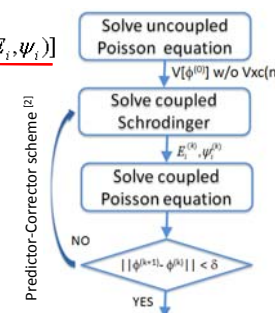
$$-\nabla \cdot (\epsilon_s \nabla \phi) = q[p(\phi) + N_D^+(\phi) - N_A^-(\phi) - n(\phi, E_i, \psi_i)]$$

Coupled Schrodinger equation:

$$-\frac{\hbar^2}{2} \nabla^2 \left(\frac{1}{m^*} \nabla \psi_i \right) + V(\phi, n) \psi_i = E_i \psi_i$$

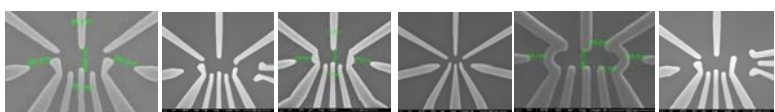
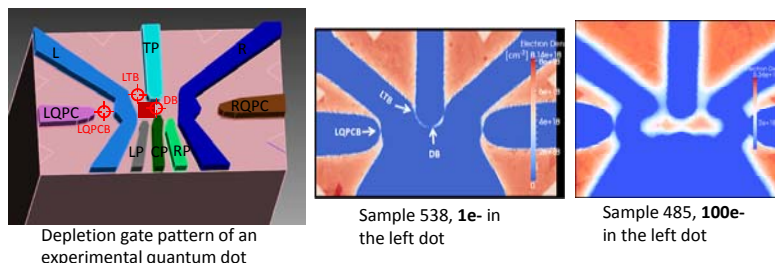
$$n(\phi, E_i, \psi_i) = \begin{cases} n(\phi) & \text{Semiclassical outside quantum region} \\ \sum_i N_i |\psi_i|^2 & \text{Quantum region} \end{cases}$$

$$V(\phi, n) = q\phi_{ref} - \chi - q\phi + V_{xc}(n)$$



Optimization & Design Guidance

- Dakota in conjunction with the QCAD Poisson Solver enables optimization of gate voltages for simultaneous targets:**
 - Electrons in a dot (e.g., 1e- in the left dot)
 - Electron density at a tunnel barrier automatically detected through saddle-point-searching algorithm (e.g., LTB, DB, LQPCB)
 - Distance b.t.w where a charge sensing constriction forms and where a dot forms

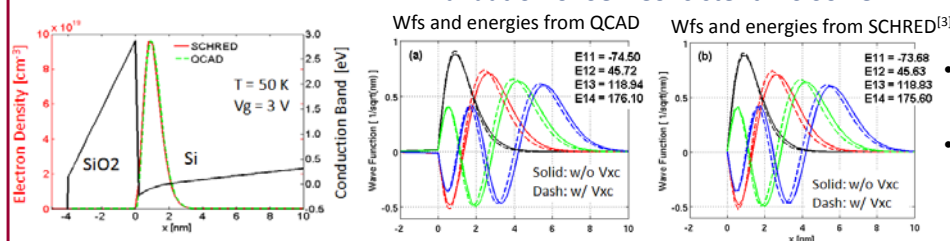


Selected SEM depletion gate patterns of experimental DQDs that have been simulated

What optimizations have been able to tell us:

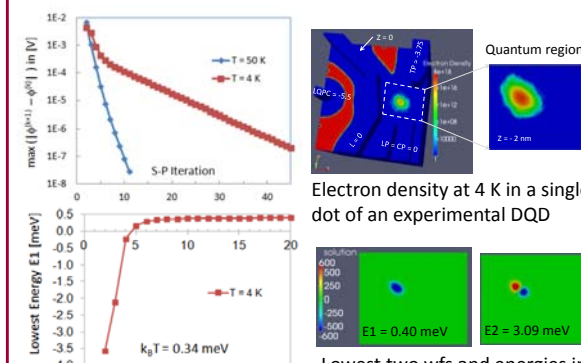
- Which experimental layouts perform better (e.g., which ones allow 1e- in each dot and simultaneously turning on barriers)
- Does barrier turn on before/after dot has many electrons? (openness)
- Location / shape of "main" dots and charge sensing barriers/dots

Validation of Self-Consistent P-S Solver



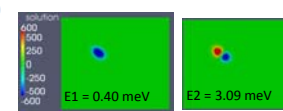
- Validate the P-S solver on a 1D MOS capacitor with 4-nm thick oxide and $5e17 \text{ cm}^{-3}$ p-substrate doping
- Also validate the solver on a 2D gate-induced quantum wire (not shown)

Application of Self-Consistent P-S to Quantum Dot



- Monotonic 3D P-S convergence
- More S-P iterations for low-T

Electron density at 4 K in a single dot of an experimental DQD



Lowest two wfs and energies in the $z=2 \text{ nm}$ plane where electron density is peaked

Simulated Dot-to-Gate Capacitances

	QCAD Poisson	QCAD 3D P-S	QCAD Poisson	QCAD Poisson	QCAD 3D P-S	QCAD 3D P-S
T = 50 K		T = 50 K		T = 4 K		T = 4 K
AG [V]	3.90	3.90	3.90	3.90	3.90	3.90
Q_0 [$\times 10^{11} \text{ cm}^{-2}$]	-4.61	-4.61	-4.51	-4.54	-4.54	-4.43
$\ln(n)$ in R_0	0.96	0.06	0.96	0.95	2.32e-19	0.95
dot-AG [aF]	3.98	1.10	4.33	4.38		4.98
dot-TP [aF]	0.33	0.07	0.37	0.37		0.44
dot-CP [aF]	0.86	0.19	0.96	0.95		1.12
dot-LP [aF]	0.64	0.14	0.72	0.71		0.84
dot-L [aF]	2.07	0.52	2.30	2.28		2.64

- For given # of e- in the dot, as T reduces, electrons stay closer to the interface, so smaller effective distance meaning higher cap.
- For given T and # of e- in the dot, quantum cap. is higher which detailed analysis shows is due to the fact that quantum charge is much broader in space, so more responsive to voltage change.

Summary

- QCAD software tool developed enables **design comparison and guidance** for semiconductor quantum dot devices.
- High throughput of simulations through scripting, automated meshing and web portal allows **fast feedback** to experiment team.
- Self-consistent quantum models in QCAD allows for **analysis of quantum effects** on device behavior (cap. etc)

[1] <http://dakota.sandia.gov> and <http://trilinos.sandia.gov>.

[2] A. Trellakis, A. T. Galick, A. Pacelli, and U. Ravaioli, J. Appl. Phys. **81**, 7880 (1997).

[3] <https://nanohub.org/tools/schred>.